

## Refine Search

Your wildcard search against 10000 terms has yielded the results below.

***Your result set for the last L# is incomplete.***

The probable cause is use of unlimited truncation. Revise your search strategy to use limited truncation.

### Search Results -

Terms	Documents
L9 same mask\$ same select\$	10

Database:

US Pre-Grant Publication Full-Text Database  
 US Patents Full-Text Database  
 US OCR Full-Text Database  
 EPO Abstracts Database  
 JPO Abstracts Database  
 Derwent World Patents Index  
 IBM Technical Disclosure Bulletins

Search:

L16

Refine Search

Recall Text

Clear

Interrupt

### Search History

DATE: Sunday, June 10, 2007   [Purge Queries](#)   [Printable Copy](#)   [Create Case](#)

<u>Set Name</u> side by side	<u>Query</u>	<u>Hit Count</u>	<u>Set Name</u> result set
DB=USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR			
<u>L16</u>	l9 same mask\$ same select\$	10	<u>L16</u>
<u>L15</u>	L11 same equation	1	<u>L15</u>
<u>L14</u>	L13 and equation	0	<u>L14</u>
<u>L13</u>	L12 and l11	3	<u>L13</u>
<u>L12</u>	mask\$ adj1 circuit\$	4433	<u>L12</u>
<u>L11</u>	L9 same compress\$	117	<u>L11</u>
<u>L10</u>	L9 same compress\$	117	<u>L10</u>
<u>L9</u>	test adj1 response	2880	<u>L9</u>
<u>L8</u>	L7 same l1	10	<u>L8</u>
<u>L7</u>	L6 same compress\$	874	<u>L7</u>
<u>L6</u>	decompress\$ adj1 circuit\$	1204	<u>L6</u>
<u>L5</u>	L4 same test\$	9	<u>L5</u>
<u>L4</u>	L1 same compress\$	149	<u>L4</u>
<u>L3</u>	L2 same compress\$	1	<u>L3</u>

<u>L2</u>	L1 same equation
<u>L1</u>	mask\$ adj1 data

55	<u>L2</u>
5864	<u>L1</u>

END OF SEARCH HISTORY

[First Hit](#)[Previous Doc](#)[Next Doc](#)[Go to Doc#](#)

Generate Collection

Print

L5: Entry 6 of 9

File: EPAB

Apr 7, 2005

DOCUMENT-IDENTIFIER: WO 2005031378 A1

TITLE: METHOD AND SYSTEM FOR SELECTIVELY MASKING TEST RESPONSES

Abstract Text (1):

CHG DATE=20050419 STATUS=O>An apparatus for testing an integrated circuit (10) that comprises a compactor (22) to compress test responses from a circuit-under-test (14) that is part of an integrated circuit (10), and masking circuitry (18) coupled between the circuit-under-test and the compactor (22) for masking one or more of the test responses from the circuit-under-test (14). The masking circuitry (18) further comprises decompression circuitry for receiving compressed mask data and providing decompressed mask data.

[Previous Doc](#)[Next Doc](#)[Go to Doc#](#)

[First Hit](#) [Fwd Refs](#)[Previous Doc](#)[Next Doc](#)[Go to Doc#](#)

Generate Collection

Print

L8: Entry 1 of 10

File: USPT

Aug 22, 2006

DOCUMENT-IDENTIFIER: US 7095808 B1

**\*\* See image for Certificate of Correction \*\***

TITLE: Code puncturing method and apparatus

## CLAIMS:

27. A method of using puncture masks comprising: retrieving a compressed puncture mask from a semiconductor memory, the compressed puncture mask being generated via a compression circuitry that compresses puncture mask data; decompressing the compressed puncture mask via a decompression circuitry to generate the puncture mask data, wherein the compressing of the puncture mask comprises: generating a first set of bits based on the puncture mask; generating a second set of bits by performing an XOR function with the first set of bits and the puncture mask; and compressing the second set or bits; and deleting particular bits from a data sequence according to the puncture mask data in the decompressed puncture mask.

34. An integrated circuit having a memory wherein the memory comprises a plurality of compressed puncture masks, each comprised puncture mask being generated via a compression circuitry that compresses puncture mask data, wherein the compressing of the puncture mask includes generating a first set of bits based on the puncture mask, generating a second set of bits by performing an XOR function with the first set of bits and the puncture mask data, and compressing the second set of bits, the compressed puncture mask being retrieved from the memory and decompressed via a decompression circuitry to generate the puncture mask data, the puncture mask data in the decompressed puncture mask being used to delete particular bits from a data sequence.

[Previous Doc](#)[Next Doc](#)[Go to Doc#](#)